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<u>L26</u>	L25 and l7	360	<u>L26</u>
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<u>L23</u>	l6 and address\$5 near5 register\$1	226	<u>L23</u>
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<u>L21</u>	16 and 19	15	<u>L21</u>
<u>L20</u>	16 and 18	5	<u>L20</u>
<u>L19</u>	16 and 17	17	<u>L19</u>
<u>L18</u>	14 and 110	11	<u>L18</u>
<u>L17</u>	14 and 19	17	<u>L17</u>
<u>L16</u>	14 and 18	5	<u>L16</u>
<u>L15</u>	14 and 17	18	<u>L15</u>
<u>L14</u>	13 and 110	11	<u>L14</u>
<u>L13</u>	13 and 19	17	<u>L13</u>
<u>L12</u>	13 and 18	5	<u>L12</u>
<u>L11</u>	13 and 17	19	<u>L11</u>
<u>L10</u>	(326/41,114,125)![CCLS]	1665	<u>L10</u>
<u>L9</u>	(716/15-19)[CCLS]	3534	<u>L9</u>
<u>L8</u>	(712/220-225)[CCLS]	1774	<u>L8</u>
<u>L7</u>	(712/2-300)[CCLS]	12719	<u>L7</u>
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<u>L5</u>	L4 and evaluat\$4	359	<u>L5</u>
<u>L4</u>	L3 and ("AND" or "OR")	588	<u>L4</u>
<u>L3</u>	L2 and (conjunct\$4 or disjunct\$4)	722	<u>L3</u>
<u>L2</u>	boolean and short near3 circuit\$3	1134	<u>L2</u>
<u>L1</u>	boolean near15 short near3 circuit\$3	28	<u>L1</u>

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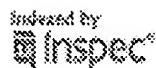
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